

Title (en)  
Methods for inspection of a specimen using different inspection parameters

Title (de)  
Verfahren zur Prüfung einer Probe mit verschiedenen Prüfparametern

Title (fr)  
Procédés d'inspection d'un spécimen utilisant différents paramètres d'inspection

Publication  
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Application  
**EP 10164279 A 20040903**

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- US 93387304 A 20040903

Abstract (en)  
Methods and systems for inspection of a specimen using different parameters are provided. One computer-implemented method includes determining optimal parameters for inspection based on selected defects. This method also includes setting parameters of an inspection system at the optimal parameters prior to inspection. Another method for inspecting a specimen includes illuminating the specimen with light having a wavelength below about 350 nm and with light having a wavelength above about 350 nm. The method also includes processing signals representative of light collected from the specimen to detect defects or process variations on the specimen. One system configured to inspect a specimen includes a first optical subsystem coupled to a broadband light source and a second optical subsystem coupled to a laser. The system also includes a third optical subsystem configured to couple light from the first and second optical subsystems to an objective, which focuses the light onto the specimen.

IPC 8 full level  
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Citation (applicant)  

- US 6266137 B1 20010724 - MORINAGA SHIROU [JP]
- US 6104481 A 20000815 - SEKINE AKIHIKO [JP], et al
- WO 0140145 A2 20010607 - KLA TENCOR CORP [US]
- US 6392793 B1 20020521 - CHUANG YUNG-HO [US], et al
- US 6392791 B1 20020521 - FORK RICHARD LYNN [US], et al

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